

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









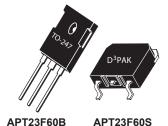


APT23F60B APT23F60S

600V, 24A, 0.29Ω Max, t_{rr} ≤220ns

N-Channel FREDFET

Power MOS 8^{TM} is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



Single die FREDFET



FEATURES

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- · ZVS phase shifted and other full bridge
- · Half bridge
- · PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I_	Continuous Drain Current @ T _C = 25°C	24	
'D	Continuous Drain Current @ T _C = 100°C	14	Α
I _{DM}	Pulsed Drain Current ^①	80	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy ©	615	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	11	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P _D	Total Power Dissipation @ T _C = 25°C			415	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.30	°C/W	
R _{ecs}	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11			
T_J , T_{STG}	Operating and Storage Junction Temperature Range	-55		150	°C	
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight		0.22		OZ	
			6.2		g	
Torque	Mounting Torque (TO-264 Package), 4-40 or M3 screw			10	in∙lbf	
				1.1	N·m	

Static Characteristics

T_J = 25°C unless otherwise specified

Α	PΤ	23	F6	0B	S
---	----	----	----	----	---

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250 \mu A$	600			V
$\Delta V_{BR(DSS)} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250µA	A	0.57		V/°C
R _{DS(on)}	Drain-Source On Resistance ^③	V _{GS} = 10V, I _D = 11A		0.23	0.29	Ω
$V_{GS(th)}$	Gate-Source Threshold Voltage	\/ -\/ -1mA	2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient	$V_{GS} = V_{DS}, I_D = 1mA$		-10		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 600V$ $T_{J} = 25^{\circ}C$			250	μA
DSS	Zero Gate voltage Drain Current	$V_{GS} = 0V$ $T_J = 125^{\circ}C$			1000	μΑ
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V			±100	nA

Dynamic Characteristics

T₁ = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
9 _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 11A		22		S
C _{iss}	Input Capacitance	V 0V V 05V		4415		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		45		
C _{oss}	Output Capacitance	1 11112		405		
C _{o(cr)} [⊕]	Effective Output Capacitance, Charge Related	$V_{GS} = 0V$, $V_{DS} = 0V$ to 400V		215		pF
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related			110		
Q _g	Total Gate Charge	\/ - 0 t- 40\/ - 444		110		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 11A,$		24		nC
Q_{gd}	Gate-Drain Charge	$V_{DS} = 300V$		46		1
t _{d(on)}	Turn-On Delay Time	Resistive Switching		25		
t _r	Current Rise Time	V _{DD} = 400V, I _D = 11A		29		ns
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 4.7\Omega^{\textcircled{6}}, V_{GG} = 15V$		75		1115
t _f	Current Fall Time	1		23		1

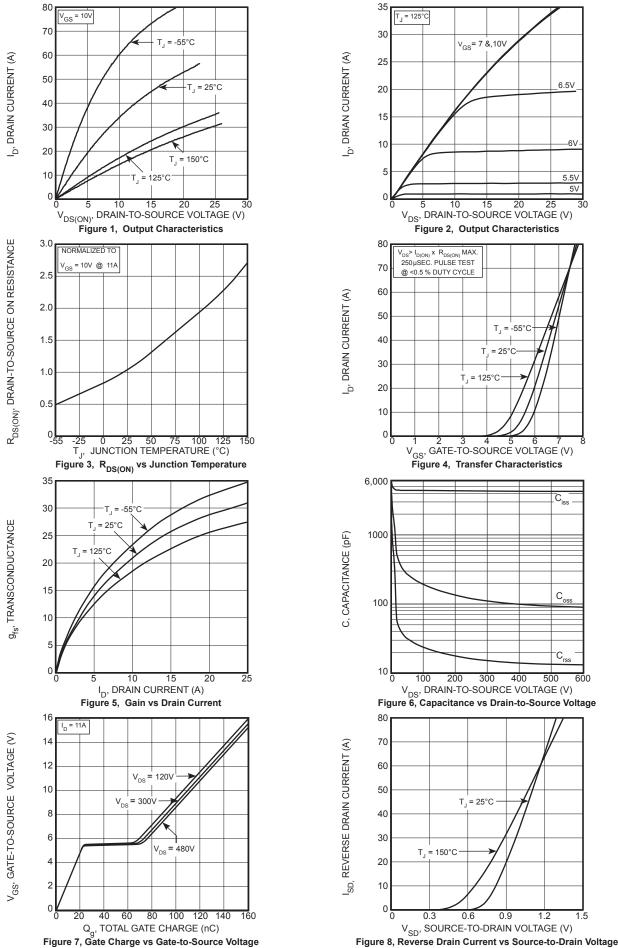
Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Is	Continuous Source Current (Body Diode)	MOSFET symbol showing the	ŞD .		24	Α
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)	s		80	
V _{SD}	Diode Forward Voltage	$I_{SD} = 11A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.2	V
t _{rr}	Reverse Recovery Time	T _J = 25°C			220	no
,u.		T _J = 125°C			400	ns
Q _{rr}	Reverse Recovery Charge	$I_{SD} = 11A^{\textcircled{3}}$ $T_{J} = 25^{\circ}C$		0.73		μC
α _{rr}		$di_{SD}/dt = 100A/\mu s$ $T_J = 125^{\circ}C$		1.79		
1	Davidson Davidson Comment	$V_{DD} = 100V$ $T_J = 25^{\circ}C$		7.3		_
'rrm	Reverse Recovery Current	T _J = 125°C		10.2		A
dv/dt	Peak Recovery dv/dt	I _{SD} ≤ 11A, di/dt ≤1000A/µs, V _{DD} = 400\ T _J = 125°C	/,		20	V/ns

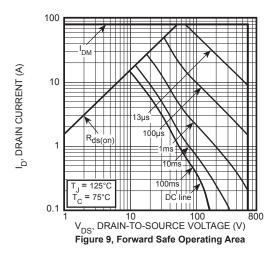
- ① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25^{\circ}C$, L = 10.17mH, $R_G = 25\Omega$, $I_{AS} = 11$ A.
- (3) Pulse test: Pulse Width < 380µs, duty cycle < 2%.

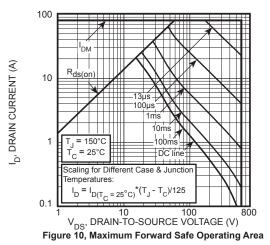
- \bigcirc R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



150-8141 Rev D 8-2011





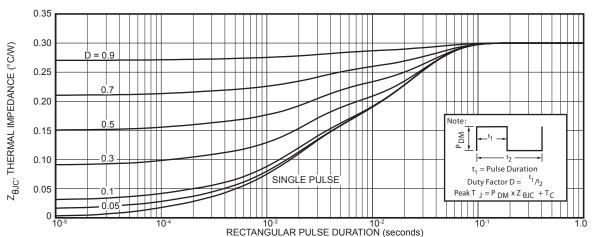
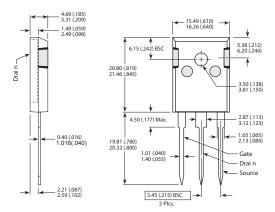


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

TO-247 (B) Package Outline

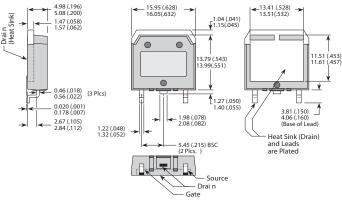
(e1) SAC: Tin, Silver, Copper



Dimensions in Millimeters (Inches)

D³PAK Package Outline

e3 100% Sn Plated



Dimensions in Millimeters (Inches)